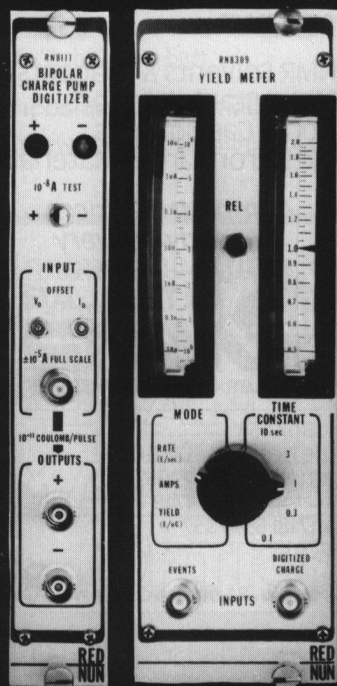


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Alabama A&M Hosts 2nd Student Conference

The Alabama A&M University Chapter of the Materials Research Society (AAMU-MRS) hosted the Second North Alabama Materials Research Student Conference on April 11, 1992, in the V. Murray Chambers Science Building on the campus of Alabama A&M University. This conference took the form of poster presentations, which ran from 8:30 a.m. until 4:00 p.m.

Calvin Lowe, chairman of the Physics Department at AAMU, delivered the opening remarks and chaired the conference. Keynote speakers were Steve Withrow of Oak Ridge National Laboratory, Jeff Sanders of the IIT Research Institute at NASA Marshall Space Flight Center, and Cardinal Warde from the Department of Electrical Engineering and Computer Science, Massachusetts Institute of Technology. Withrow described "Annealing of Damage in Doped Si Using Ion Beams," Sanders spoke on "High-Temperature Oxidation of Fe-Ni Superalloys," and Warde spoke about "Photo-refractive BaTiO_3 ."

The best presenters were recognized:

■ **First Prize:** "Ultrasonic Cavitation Effects on the Physical and Optical Properties of Ceramics," Yolanda M. Powell (presenter), AAMU; Lynn A. Boatner and James Brewster, Oak Ridge National Laboratory; Daryush Ila, AAMU.

■ **Second Prize:** "Density Functional Calculations of Positron Annihilation Rates: Analysis of the Role of Electron-Positron Correlation," K. Kim (presenter) and J.G. Harrison, University of Alabama at Birmingham.

■ **Third Prize:** "Second and Third Harmonic Generation by Reflection from Langmuir-Blodgett films of New Organic Material," R. Srinivasan (presenter), P. Venkateswarlu, K.X. He, H.W. Hyde, B.G. Penn, and D.O. Frazier, AAMU. "Application of $p\text{-}\alpha$ Reactions for the Detection of Light Elements in Crystals and Solids," Thomas Taylor (presenter), Eric K. Williams, and Daryush Ila, AAMU. "Study of the Carbonization of Phenolformaldehyde Resin at High Temperatures," Leslie Evelyn (presenter), G.M. Jenkins, D. Ila, and L.R. Holland, AAMU; R.L. Zimmerman, University of Sao Paulo, Brazil.

Daryush Ila of AAMU's Physics Department and adviser to AAMU-MRS delivered the closing remarks. Co-sponsors of the conference included the Alabama Space Grant Consortium, ASM (North Alabama Chapter), MRS, and Oak Ridge National Laboratory. □

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To request detailed 1992 Fall program, short course, or symposium aide information, contact:



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